



PALM INTRANET

Day : Tuesday
 Date: 3/25/2003
 Time: 11:04:46

Inventor Name Search Result

Your Search was:

Last Name = NAKATA

First Name = YOSHIRO

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<u>08638038</u>	<u>5829126</u>	150	04/26/1996	METHOD OF MANUFACTURING PROBE CARD	NAKATA , YOSHIRO
<u>08650486</u>	<u>5665610</u>	150	05/17/1996	SEMICONDUCTOR DEVICE CHECKING METHOD	NAKATA , YOSHIRO
<u>06426276</u>	<u>4614586</u>	250	09/29/1982	SEMIERMEABLE POLYMERIC FILM MEMBRANE	NAKATA , YOSHIRO
<u>07848840</u>	<u>5214296</u>	150	03/10/1992	THIN-FILM SEMICONDUCTOR DEVICE AND METHOD OF FABRICATING THE SAME	NAKATA , YOSHIRO
<u>09176194</u>	<u>6297658</u>	150	10/21/1998	WAFER BURN-IN CASSETTE AND METHOD OF MANUFACTURING PROBE CARD FOR USE THEREIN	NAKATA , YOSHIRO
<u>08943411</u>	<u>5983331</u>	150	09/30/1997	SEMICONDUCTOR INTEGRATED CIRCUIT HAVING A PLURALITY OF CHIPS	NAKATA , YOSHIRO
<u>07882064</u>	<u>5315543</u>	150	05/12/1992	SEMICONDUCTOR MEMORY DEVICE AND A MANUFACTURING METHOD THEREOF	NAKATA , YOSHIRO
<u>07915898</u>	<u>5300814</u>	150	07/17/1992	SEMICONDUCTOR DEVICE HAVING A SEMICONDUCTOR SUBSTRATE WITH REDUCED STEP BETWEEN MEMORY CELLS	NAKATA , YOSHIRO
<u>08065123</u>	<u>5355081</u>	150	05/20/1993	A METHOD FOR TESTING A SEMICONDUCTOR INTEGRATED CIRCUIT HAVING SELF TESTING CIRCUIT	NAKATA , YOSHIRO

<u>07456994</u>	<u>5006717</u>	150	12/26/1989	METHOD OF EVALUATING A SEMICONDUCTOR DEVICE AND AN APPARATUS FOR PERFORMING THE SAME	NAKATA , YOSHIRO
<u>07710788</u>	Not Issued	161	06/05/1991	SEMICONDUCTOR MEMORY DEVICE AND ITS FABRICATING METHOD	NAKATA , YOSHIRO
<u>09174536</u>	<u>6518779</u>	150	10/19/1998	PROBE CARD	NAKATA , YOSHIRO
<u>08530428</u>	Not Issued	166	09/19/1995	A SEMICONDUCTOR INTEGRATED CIRCUIT HAVING A PLURALITY OF CHIPS	NAKATA , YOSHIRO
<u>08257955</u>	<u>5399890</u>	150	06/10/1994	SEMICONDUCTOR MEMORY DEVICE IN WHICH A CAPACITOR ELECTRODE OF A MEMORY CELL AND AN INTERCONNECTION LAYER OF A PERIPHERAL CIRCUIT ARE FORMED IN ONE LEVEL	NAKATA , YOSHIRO
<u>07699950</u>	Not Issued	166	05/14/1991	SEMICONDUCTOR MEMORY DEVICE CAPACITOR HAVING PLURAL PARALLEL PLATE ELECTRODES AND CONNECTING SIDE-WALL ELECTRODE	NAKATA , YOSHIRO
<u>07683603</u>	<u>5217914</u>	150	04/10/1991	METHOD FOR MAKING SEMICONDUCTOR INTEGRATION CIRCUIT WITH STACKED CAPACITOR CELLS	NAKATA , YOSHIRO
<u>07678150</u>	<u>5241201</u>	150	04/02/1991	DRAM WITH CONCENTRIC ADJACENT CAPACITORS	NAKATA , YOSHIRO
<u>08575735</u>	<u>5825193</u>	150	12/18/1995	SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE	NAKATA , YOSHIRO
<u>09140323</u>	<u>6229329</u>	150	08/26/1998	METHOD OF TESTING ELECTRICAL CHARACTERISTICS OF MULTIPLE SEMICONDUCTOR INTEGRATED CIRCUITS SIMULTANEOUSLY	NAKATA , YOSHIRO

<u>08624954</u>	<u>5605844</u>	150	03/27/1996	INSPECTING METHOD FOR SEMICONDUCTOR DEVICES	NAKATA , YOSHIRO
<u>08060695</u>	Not Issued	161	05/13/1993	SEMICONDUCTOR MEMORY DEVICE CAPACITOR HAVING PLURAL PARALLEL PLATE ELECTRODES AND CONNECTING SIDE-WALL ELECTRODES	NAKATA , YOSHIRO
<u>07767998</u>	<u>5248936</u>	150	09/30/1991	SEMICONDUCTOR INTEGRATED CIRCUIT AND A METHOD OF TESTING THE SAME	NAKATA , YOSHIRO
<u>08744082</u>	<u>5892368</u>	150	11/04/1996	SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE HAVING FAILURE DETECTION CIRCUITRY	NAKATA , YOSHIRO
<u>07964720</u>	Not Issued	166	10/22/1992	SEMICONDUCTOR MEMORY AND METHOD OF FABRICATING THE SAME	NAKATA , YOSHIRO
<u>09198445</u>	<u>6215321</u>	150	11/24/1998	PROBE CARD FOR WAFER-LEVEL MEASUREMENT, MULTILAYER CERAMIC WIRING BOARD, AND FABRICATING METHODS THEREFOR	NAKATA , YOSHIRO
<u>07310624</u>	Not Issued	166	02/15/1989	MOLDABLE COMPOSITION, PROCESS FOR PRODUCING SINTERED BODY THEREFROM AND PRODUCTS FROM SAME	NAKATA , YOSHIROH
<u>07733979</u>	<u>5432224</u>	150	07/22/1991	MOLDABLE COMPOSITION, PROCESS FOR PRODUCING SINTERED BODY THEREFROM AND PRODUCTS FROM SAME	NAKATA , YOSHIROH
<u>08358609</u>	Not Issued	166	12/14/1994	SEMICONDUCTOR WAFER PACKAGE, METHOD AND APPARATUS FOR CONNECTING TESTING IC TERMINALS OF SEMICONDUCTOR WAFER AND PROBE TERMINALS, TESTING METHOD OF A SEMICONDUCTOR INTEGRATED CIRCUIT,	NAKATA , YOSHIROU

				PROBE CARD AND ITS MANUFACTURING METHOD	
<u>09396884</u>	<u>6323663</u>	150	09/16/1999	SEMICONDUCTOR WAFER PACKAGE, METHOD AND APPARATUS FOR CONNECTING TESTING IC TERMINALS OF SEMICONDUCTOR WAFER AND PROBE TERMINALS, TESTING METHOD OF A SEMICONDUCTOR INTEGRATED CIRCUIT, PROBE CARD AND ITS MANUFACTURING METHOD	NAKATA , YOSHIROU
<u>08837954</u>	<u>6005401</u>	150	04/14/1997	SEMICONDUCTOR WAFER PACKAGE, METHOD AND APPARATUS FOR CONNECTING TESTING IC TERMINALS OF SEMICONDUCTOR WAFER AND PROBE TERMINALS, TESTING METHOD OF A SEMICONDUCTOR INTEGRATED CIRCUIT, PROBE CARD AND ITS MANUFACTURING METHOD	NAKATA , YOSHIROU
<u>08609150</u>	<u>5945834</u>	150	02/29/1996	SEMICONDUCTOR WAFER PACKAGE, METHOD AND APPARATUS FOR CONNECTING TESTING IC TERMINALS OF SEMICONDUCTOR WAFER AND PROBE TERMINALS, TESTING METHOD OF A SEMICONDUCTOR INTEGRATED CIRCUIT, PROBE CARD AND ITS MANUFACTURING METHOD	NAKATA , YOSHIROU
<u>09964480</u>	Not Issued	030	09/28/2001	SEMICONDUCTOR INTEGRATED CIRCUIT TESTING SYSTEM AND METHOD	NAKATA, YOSHIRO
<u>10322571</u>	Not Issued	030	12/19/2002	METHOD OF TESTING SEMICONDUCTOR	NAKATA, YOSHIRO

				INTEGRATED CIRCUITS AND TESTING BOARD FOR USE THEREIN	
<u>09811422</u>	<u>6400175</u>	150	03/20/2001	METHOD OF TESTING SEMICONDUCTOR INTEGRATED CIRCUITS AND TESTING BOARD FOR USE THEREIN	NAKATA, YOSHIRO
<u>10127580</u>	Not Issued	041	04/23/2002	METHOD OF TESTING SEMICONDUCTOR INTEGRATED CIRCUITS AND TESTING BOARD FOR USE THEREIN	NAKATA, YOSHIRO
<u>08088908</u>	Not Issued	166	07/08/1993	IMAGE RECORDING APPARATUS	NAKATANI, YOSHIRO

Inventor Search Completed: No Records to Display.

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